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CONSOLIDATED VERSION

Metallic cables and other passive components test methods - Part 4-7: Electromagnetic compatibility (EMC) -Test method for measuring of transfer impedance Z_T and screening attenuation as or coupling attenuation ac of connectors and assemblies - Triaxial tube in tube method

<u> 1EC 62153-4-7:2021</u>

https://standards.iteh.ai/catalog/standards/jec/42h7ec6a-a396-4206-81a5-5a0c451bfeba/jec-62153-4-7-2021



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Preview

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